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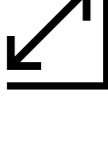

Prof. Dr. Han Haitjema

Current Topics

Traceability to SI units of complex measurement systems;
Measurement theory in a broad context;
Measurement uncertainty and uncertainty evaluation;
Considerations on the fundamentals of measurement;
Error separation methods;
Novel methods inspired by the redefinition of the SI;
Cyberphysical systems;
Artificial intelligence, especially its effect on traceability;
Machine learning for metrology;

Precision measurement;
Digital twins;
Metrology for sustainable manufacturing;
Precision manufacturing;
Measurement techniques and devices;
Interferometry;
XCT measurements;
3D metrology;
Frequency metrology;
Surface metrology;
Biomedical measurement;
Virtual measurement;
Power measurement.

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